University of California at Berkeley College of Engineering Dept. of Electrical Engineering and Computer Sciences

EECS 40 Midterm II

Fall 1998	Prof. Roger T. Howe	November 19, 1998

Guidelines	3

- 1. Closed Book and notes; one 8.5" x 11" page (both sides) of your own notes is allowed.
- 2. You may use a Calculator

Name: _____

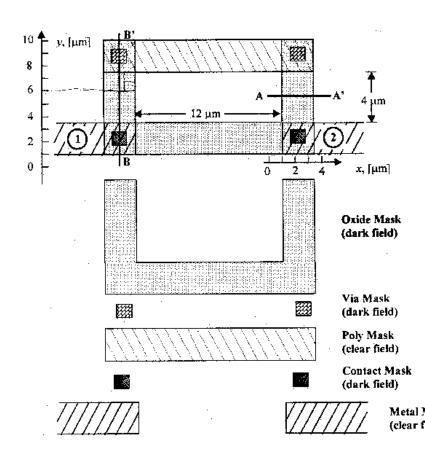
Student ID:

- 3. Do not unstaple the exam.
- 4. Show all your work and reasoning on the exam in order to receive full or partial credit.

Score

Problem	Possible Points	Score
1	24	
2	18	
3	8	
Total	50	

1. Integrated Circuit Structure [24 points]



Process Sequence:

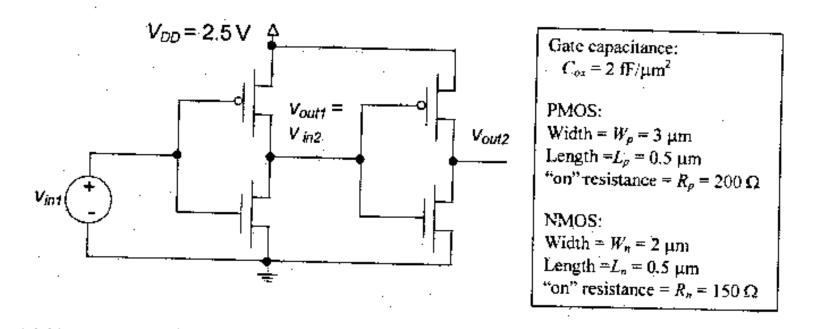
- 1. Starting Material: boron-doped silicon, concentration 5 x 10¹⁶ cm⁻³
- 2. Deposit 250 nm of silicon dioxide and pattern using the **oxide mask** (dark field)
- 3. Implant phosphorus and anneal (depth 500 nm and concentration 1.25 x 10¹⁷ cm⁻³
- 4. Deposit 250 nm of slicon dioxide and then etch 250 nm of oxide using the via mask (dark field).
- 5. Deposit 250 nm of aresenic-doped polysiliconsilicon and pattern using the **polymask** (clear field). The arsenic concentration is $5 \times 10^{18} \, \text{cm}^{-3}$
- 6. Deposit 250 nm of silicon dioxide and then etch 500 nm of oxide using the **contact mask** (dark field).
- 7. Depoist 500 nm of aluminum and pattern using the **metal mask** (clear field).

Given:
$$\begin{aligned} & \underset{silicon:}{\text{single cyrstal}} & & \underset{nu_n}{\text{mu}_n} = 1000 \text{ cm} \, ^2/\\ & & \text{volution:} \end{aligned} \qquad \begin{aligned} & \underset{polysilicon:}{\text{mu}_n} = 400 \text{ cm} \, ^2/(Vs) \\ & & \text{mu}_p = 400 \text{ cm} \, ^2/(Vs) \end{aligned} \qquad \qquad \end{aligned} \\ & \underset{polysilicon:}{\text{mu}_n} = 100 \text{ cm} \, ^2/(Vs) \qquad \qquad \end{aligned} \\ & \underset{polysilicon:}{\text{mu}_p} = 50 \text{ cm} \, ^2/(Vs) \end{aligned}$$

(a) [8 pts.] Sketch the cross section **A-A'** on the graph below. Identify all layers clearly.

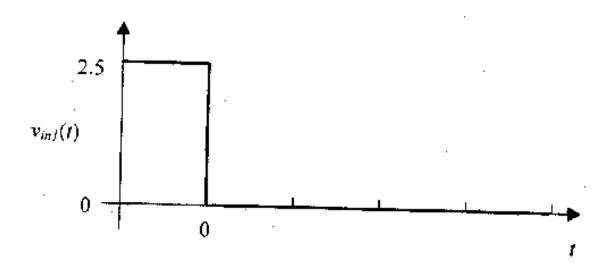
(e) [4pts] What is the numerical value of the resistance between terminals 1 and 2? You can neglect the "end squares" at connections between the conducting layers. If you have ano answers for parts (c) and (d), you can use $R_{\text{square, poly}}$ of = 250 ohms/square for the polysilicon layer and that $R_{\text{square, implant}} = 150$ ohms/square for the phosphorus implanted layare for this part.

2. CMOS inverter pair [18 points]



(a) [4pts.] This inverter pair also been "at rest" for some time with its input "high." The wave for for $v_{in1}(t)$ is sketched

below. Draw teh switch-model circuit for finding the output voltage $v_{out1}(t)$ of inverter 1 for t > 0. Provide some numerical values for the circuit elements. You can neglect the drain-bulk capacitances and any wire capacitance.

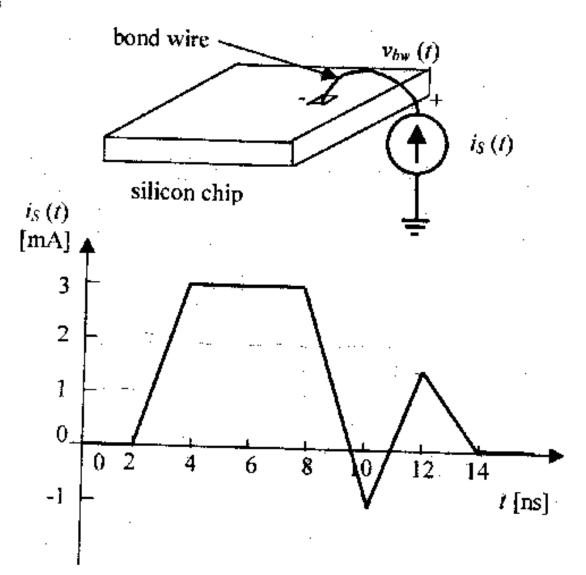


(b) [4 pts.] Determine the wave form $v_{\text{out1}}(t)(t)$ for t>0.

(c) [4pts.] Due to contamination of the gate oxide furnace, you discover that the gate oxide is not a perfect insulator, but instead is modeled by a resistance $R_G = 1$ kOhm in parallel with the gate-source capacitance (C_{Gn} for the NMOS, C_{Gp} for the PMOS). Repeat part (a) using these "leaky" NMOS and PMOS transistors for both inverters.

(d) [3pts] What is the value of $v_{out1}(t)(t<0)$ for the circuit in part (c), assuming the input wave form $v_{in1}(t)$ that is given in

part (a). Note that the inverter has had a "high" input for a long time before its input transitions at $t = 0$.
(e) [3pts.] What is the value of $v_{out1}(t)$ (t approaches infiniti) for the circuit in part (c), assuming the input waveform $v_{in1}(t)$ 1 (t) that is given in part (a). Hint: consider superposition.
3. Bond wire inductance [8 points]



(a) [5pts] The bond wire can be modeled by a 1 nH inductor. Given the wave form for the supply current $i_s(t)$, plot the voltage drop across the bondwire $v_{bw}(t)$ on the graph below.

(b) [3pts] A particular circuit can tolerat at most $|v_{bw}(t)| = 250$ micro - V for a critical application. How many bondwires are needed to meet this requirement, given the $i_s(t)$ waevform? Hint: consider whether series or parallel bond wires will help.

Posted by HKN (Electrical Engineering and Computer Science Honor Society
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